

Notice of References Cited

Application/Control No.

10/528,243

Applicant(s)/Patent Under
Reexamination
YONEYAMA ET AL.

Examiner

Anna L. Verderame

Art Unit

1756

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0028287	03-2002	Kawada et al.	427/163.1
*	B	US-2001/0041242	11-2001	Hayashida et al.	428/64.4
*	C	US-2002/0054975	05-2002	Hayashida et al.	428/64.4
*	D	US-2002/0139939	10-2002	Takayama et al.	250/492.3
*	E	US-2001/0028456	10-2001	Nishi, Kenji	356/400
*	F	US-2003/0017368	01-2003	Wu et al.	428/694.0TF
*	G	US-6,961,113	11-2005	Hayashi et al.	355/30
*	H	US-2002/0176957	11-2002	Mino et al.	428/64.6
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 62155965	07-1987	Japan	Tsuboi et al	
	O	WO 00/74120	05-2000	Japan	Hayashi et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.